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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of: **POIROUX ET AL.**	
Serial No. **10/672,931**	Attorney Docket No. **54480**
Filing Date: **SEPTEMBER 26, 2003**	
For: **PROCESS AND DEVICE FOR EVALUATING A CMOS LOGICAL CELL**	

CITATION UNDER 37 CFR §1.97

COMMISSIONER FOR PATENTS
P.O. BOX 1450
ALEXANDRIA, VA 22313-1450

Sir:

Attached is Form PTO-1449 listing several references for consideration in the examination of the above-identified application. A copy of each reference is also enclosed. It is requested that these references be considered by the Examiner and officially made of record in accordance with the provisions of 37 CFR §1.97 and Section 609 of the MPEP.

Respectfully submitted,

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Cas No. 02GR2182(54480)

COMMISSIONER FOR PATENTS
P.O. BOX 1450
ALEXANDRIA, VA 22313-1450

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Serial No.:	**10/672,931**
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Sir:

Transmitted herewith is an INFORMATION DISCLOSURE STATEMENT in the above-identified application.

1. [X] This IDS is submitted under 37 C.F.R. § 1.97. No fee is required.
2. [] This IDS is submitted under 37 C.F.R. § 1.97(c). Enclosed is a check in in the amount of $ 180.00.
3. [] This IDS is submitted under 37 C.F.R. § 1.97(c) and (e). No fee is required.
4. [] This IDS is submitted under 37 C.F.R. § 1.97(d) and (e). Enclosed is a check in the amount of $130.00 to cover the petition fee.
5. [X] The Commissioner is hereby authorized to charge or credit any discrepancies in fee amounts to Deposit Account No. 01-0484.
6. [X] Please associate this application with Customer No. 27975.



PATENT TRADEMARK OFFICE

Date: October 14, 2003

PAUL J. DITMYER
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OCT 17 2003
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In re Patent Application of
BOIROUX ET AL.
Serial No. **10/672,931**
Filed: **SEPTEMBER 26, 2003**

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CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 14th day of October, 2003.

Dawn K. Kimler

OIPE JC54 OCT 17 2003 PATENT & TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT	Atty Docket:	02GR2182(54480)
	Serial No.:	10/672,931
	Applicant:	POIROUX ET AL.
	Filing Date:	SEPTEMBER 26, 2003
	Group:	

U.S. PATENT DOCUMENTS

Examiner Initials		Document Number	Date	Name	Class	Sub Class	Filing Date
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub Class	Translation
	AJ						
	AK						

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

	AL	Faynot et al., "Compact Analytical Modeling of SOI Partially Depleted MOSFETs with LETISOI", Solid State Electronics, Elsevier Science Publishers, Barking, Great Britain, vol. 45, no. 4, April 2001, pp. 599-605 ISSN: 0038-1101
	AM	Shepard et al., "Body-Voltage Estimation in Digital PD-SOI Circuits and its Application to Static Timing Analysis", Computer-Aided Design, 1999. Digest of Technical Papers, 1999, IEEE/ACM International Conference on San Jose, CA, USA 7-11 November 1999, Piscataway, NJ, USA, IEEE, US, November 7, 1999, pages 531-538, XP010363841
	AN	Aller et al., "Detailed Analysis of the Gate Delay Variability in Partially Depleted SOI CMOS Circuits", SOI Conference, 1999 proceedings, 1999 IEEE International Rohnert Park, CA, USA 4-7 October 1999, Piscataway, NJ, USA, IEEE, US, October 4, 1999, pages 40-41, XP010370224, ISBN: 0-7803-5456-7
	AO	Xilin et al., "SOI Device and Technology: Modeling, Characterization, and Simulations", 2001 6th International Conference on Solid-State and Integrated Circuit Technology Proceedings (CAT. No. 01EX443), Proceedings of 6th International Conference on Solid-State and IC Technology, Shanghai, China, 22-25 October 2001, pages 643-649, Voll. 1, XP010576049 2001, Piscataway, NJ, USA, IEEE, USA, ISBN: 0-7803-6520-8

EXAMINER:	DATE CONSIDERED:

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.